

12 track Standard Cell Library comprising of cells for clock network (Balanced cells, Clock-gating cells) and Metastable tolerant Flip-flop

Overview

Features

- The C28SOI_SC_12_CLK_LR Standard Cell library contains 332 cells.

Application

- Design needs in CMOS28FDSOI platform IPs.

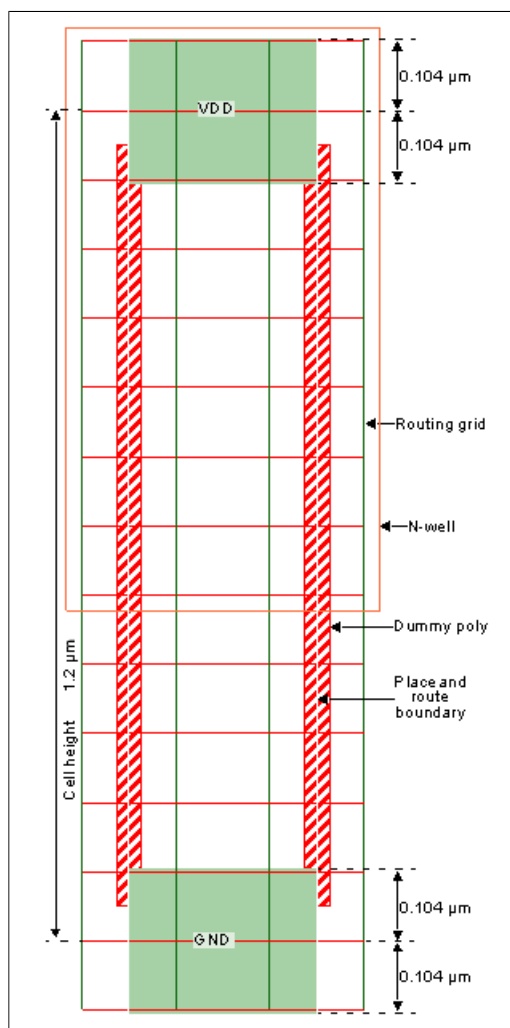
Library Architecture

This section illustrates the architecture used for C28SOI_SC_12_CLK_LR Standard Cell library.

Following table shows the Physical Specifications for this library.

Physical Specifications	
Parameter	Measurement
Drawn Gate Length (um)	0.030
Layout Grid (um)	0.001
Vertical Pin Grid (um)	0.1
Horizontal Pin Grid (um)	0.136
Cell Power and Ground Rail Width (um)	0.208

Figure 1: Cell Architecture



1. Quick References



Please refer to the Naming Convention Document available in Design Package for more details regarding cell names.



Please refer to the Standard Cells Reference Manual available in Design Package for more details on library specific information.

2. Functional Specification

2.1. Cell Info

2.1.1. LR(LP Regular Vt)

2.1.1.1. Poly Bias With 0nm

Table 2: Cell List

Cell Type	Drive Strength	Cell Description
C12T28SOI_LR_CNIV	X133, X16, X23, X31, X39, X47, X55, X5, X61, X70, X8, X94	Inverter with Balanced rise and fall delays for Clock network
C12T28SOIDV_LR_CNGFMUX21	X15, X30	2:1 Glitch-free MUX for Clock network,Vdd rail at the bottom of the cell
C12T28SOI_LR_CNAND2	X15, X20, X33	2 input AND for Clock network
C12T28SOIDV_LR_CNMUX41	X17, X27	4:1 non-inverting Multiplexer for Clock network,Vdd rail at the bottom of the cell
C12T28SOI_LR_CNAND3	X17, X25, X33	3 input AND for Clock network
C12T28SOIDV_LR_SDFSYNCPQ	X8	Metastable tolerant; Positive edge triggered Scan D flip-flop; having non-inverted output Q only,Vdd rail at the bottom of the cell
C12T28SOIDV_LR_SDFSYNCP SQ	X8	Metastable tolerant; Positive edge triggered Scan D flip-flop; with active low asynchronous Preset; having non-inverted output Q only,Vdd rail at the bottom of the cell
C12T28SOI_LR_CNSDFPSQT	X15	Positive edge triggered Scan D flip-flop; with active low asynchronous Preset; having non-inverted output Q and non-inverted test output TQ for Clock network
C12T28SOI_LR_CNLDLRQ	X33	Active Low transparent Latch; with active low asynchronous Reset; having non-inverted output Q only
C12T28SOI_LR_CNNOR2A	X15, X27	2 input NOR with A input Inverted for Clock network
C12T28SOI_LR_DLYHFM4	X15, X7	Delay Cell for Hold Time Fixing
C12T28SOI_LR_CNNAND2	X15, X33	2 input NAND for Clock network
C12T28SOI_LR_DLYHFM8	X15, X54, X7	Delay Cell for Hold Time Fixing
C12T28SOI_LR_CNSDFPRQT	X15	Positive edge triggered Scan D flip-flop; with active low asynchronous Reset; having non-inverted output Q and non-inverted test output TQ for Clock network
C12T28SOI_LRP_CNHLS	X15, X22, X29, X36, X51, X58, X71, X7, X93	Design optimized to reduce dynamic power, Latch-based clock gating integrated cell; having active high enable clock transparent and active low enable clock hold low; with scan functionality for Clock network
C12T28SOI_LR_CNAO12	X33	2 input AND into 2 input OR
C12T28SOI_LR_CNOR4	X20, X27	4 input OR for Clock network

Cell Type	Drive Strength	Cell Description
C12T28SOI_LR_CNMUX21	X17, X33	2:1 non-inverting Multiplexer for Clock network
C12T28SOI_LR_CNBF	X133, X15, X22, X30, X38, X44, X4, X52, X59, X70, X7, X94	Buffer with Balanced rise and fall delays for Clock network
C12T28SOI_LR_CNOR3	X14, X20, X27	3 input OR for Clock network
C12T28SOI_LR_CNOR2	X15, X20, X33, X37	2 input OR for Clock network
C12T28SOI_LRPHP_CNHLS	X29, X36, X44, X51, X58, X71, X86	Design optimized to reduce dynamic power, Latch-based clock gating integrated cell; having active high enable clock transparent and active low enable clock hold low; with scan functionality for Clock network
C12T28SOI_LR_CNNOR2	X14, X33	2 input NOR for Clock network
C12T28SOI_LR_CNNAND2A	X17, X27	2 input NAND with A input inverted for Clock network
C12T28SOIDV_LR_SDFSYNCPRQ	X8	Metastable tolerant; Positive edge triggered Scan D flip-flop; with active low asynchronous Reset; having non-inverted output Q only, Vdd rail at the bottom of the cell
C12T28SOI_LR_CNXOR2	X16, X27	2 input Exclusive OR for Clock network

2.1.1.2. Poly Bias With 4nm

Table 3: Cell List

Cell Type	Drive Strength	Cell Description
C12T28SOI_LR_CNIV	X133, X16, X23, X31, X39, X47, X55, X5, X61, X70, X8, X94	Inverter with Balanced rise and fall delays for Clock network
C12T28SOIDV_LR_CNGFMUX21	X15, X30	2:1 Glitch-free MUX for Clock network, Vdd rail at the bottom of the cell
C12T28SOI_LR_CNAND2	X15, X20, X33	2 input AND for Clock network
C12T28SOIDV_LR_CNMUX41	X17, X27	4:1 non-inverting Multiplexer for Clock network, Vdd rail at the bottom of the cell
C12T28SOI_LR_CNAND3	X17, X25, X33	3 input AND for Clock network
C12T28SOIDV_LR_SDFSYNCPQ	X8	Metastable tolerant; Positive edge triggered Scan D flip-flop; having non-inverted output Q only, Vdd rail at the bottom of the cell
C12T28SOIDV_LR_SDFSYNCPQS	X8	Metastable tolerant; Positive edge triggered Scan D flip-flop; with active low asynchronous Preset; having non-inverted output Q only, Vdd rail at the bottom of the cell
C12T28SOI_LR_CNSDFPSQT	X15	Positive edge triggered Scan D flip-flop; with active low asynchronous Preset; having non-inverted output Q and non-inverted test output TQ for Clock network
C12T28SOI_LR_CNLDLRQ	X33	Active Low transparent Latch; with active low asynchronous Reset; having non-inverted output Q only

Cell Type	Drive Strength	Cell Description
C12T28SOI_LR_CNNOR2A	X15, X27	2 input NOR with A input Inverted for Clock network
C12T28SOI_LR_DLYHFM4	X15, X7	Delay Cell for Hold Time Fixing
C12T28SOI_LR_CNNAND2	X15, X33	2 input NAND for Clock network
C12T28SOI_LR_DLYHFM8	X15, X54, X7	Delay Cell for Hold Time Fixing
C12T28SOI_LR_CNSDFPRQT	X15	Positive edge triggered Scan D flip-flop; with active low asynchronous Reset; having non-inverted output Q and non-inverted test output TQ for Clock network
C12T28SOI_LRP_CNHLS	X15, X22, X29, X36, X51, X58, X71, X7, X93	Design optimized to reduce dynamic power, Latch-based clock gating integrated cell; having active high enable clock transparent and active low enable clock hold low; with scan functionality for Clock network
C12T28SOI_LR_CNAO12	X33	2 input AND into 2 input OR
C12T28SOI_LR_CNOR4	X20, X27	4 input OR for Clock network
C12T28SOI_LR_CNMUX21	X17, X33	2:1 non-inverting Multiplexer for Clock network
C12T28SOI_LR_CNBF	X133, X15, X22, X30, X38, X44, X4, X52, X59, X70, X7, X94	Buffer with Balanced rise and fall delays for Clock network
C12T28SOI_LR_CNOR3	X14, X20, X27	3 input OR for Clock network
C12T28SOI_LR_CNOR2	X15, X20, X33, X37	2 input OR for Clock network
C12T28SOI_LRPHP_CNHLS	X29, X36, X44, X51, X58, X71, X86	Design optimized to reduce dynamic power, Latch-based clock gating integrated cell; having active high enable clock transparent and active low enable clock hold low; with scan functionality for Clock network
C12T28SOI_LR_CNNOR2	X14, X33	2 input NOR for Clock network
C12T28SOI_LR_CNNAND2A	X17, X27	2 input NAND with A input inverted for Clock network
C12T28SOIDV_LR_SDFSYNCPRQ	X8	Metastable tolerant; Positive edge triggered Scan D flip-flop; with active low asynchronous Reset; having non-inverted output Q only, Vdd rail at the bottom of the cell
C12T28SOI_LR_CNxor2	X16, X27	2 input Exclusive OR for Clock network

2.1.1.3. Poly Bias With 10nm

Table 4: Cell List

Cell Type	Drive Strength	Cell Description
C12T28SOI_LR_CNIV	X133, X16, X23, X31, X39, X47, X55, X5, X61, X70, X8, X94	Inverter with Balanced rise and fall delays for Clock network
C12T28SOIDV_LR_CNGFMUX21	X15, X30	2:1 Glitch-free MUX for Clock network, Vdd rail at the bottom of the cell
C12T28SOI_LR_CNAND2	X15, X20, X33	2 input AND for Clock network
C12T28SOIDV_LR_CNMUX41	X17, X27	4:1 non-inverting Multiplexer for Clock network, Vdd rail at the bottom of the cell

Cell Type	Drive Strength	Cell Description
C12T28SOI_LR_CNAND3	X17, X25, X33	3 input AND for Clock network
C12T28SOIDV_LR_SDFSYNCPQ	X8	Metastable tolerant; Positive edge triggered Scan D flip-flop; having non-inverted output Q only, Vdd rail at the bottom of the cell
C12T28SOIDV_LR_SDFSYNCP SQ	X8	Metastable tolerant; Positive edge triggered Scan D flip-flop; with active low asynchronous Preset; having non-inverted output Q only, Vdd rail at the bottom of the cell
C12T28SOI_LR_CNSDFPSQT	X15	Positive edge triggered Scan D flip-flop; with active low asynchronous Preset; having non-inverted output Q and non-inverted test output TQ for Clock network
C12T28SOI_LR_CNLDLRQ	X33	Active Low transparent Latch; with active low asynchronous Reset; having non-inverted output Q only
C12T28SOI_LR_CNNOR2A	X15, X27	2 input NOR with A input Inverted for Clock network
C12T28SOI_LR_DLYHFM4	X15, X7	Delay Cell for Hold Time Fixing
C12T28SOI_LR_CNNAND2	X15, X33	2 input NAND for Clock network
C12T28SOI_LR_DLYHFM8	X15, X54, X7	Delay Cell for Hold Time Fixing
C12T28SOI_LR_CNSDFPRQT	X15	Positive edge triggered Scan D flip-flop; with active low asynchronous Reset; having non-inverted output Q and non-inverted test output TQ for Clock network
C12T28SOI_LRP_CNHLS	X15, X22, X29, X36, X51, X58, X71, X7, X93	Design optimized to reduce dynamic power, Latch-based clock gating integrated cell; having active high enable clock transparent and active low enable clock hold low; with scan functionality for Clock network
C12T28SOI_LR_CNAO12	X33	2 input AND into 2 input OR
C12T28SOI_LR_CNOR4	X20, X27	4 input OR for Clock network
C12T28SOI_LR_CNMUX21	X17, X33	2:1 non-inverting Multiplexer for Clock network
C12T28SOI_LR_CNBF	X133, X15, X22, X30, X38, X44, X4, X52, X59, X70, X7, X94	Buffer with Balanced rise and fall delays for Clock network
C12T28SOI_LR_CNOR3	X14, X20, X27	3 input OR for Clock network
C12T28SOI_LR_CNOR2	X15, X20, X33, X37	2 input OR for Clock network
C12T28SOI_LRPHP_CNHLS	X29, X36, X44, X51, X58, X71, X86	Design optimized to reduce dynamic power, Latch-based clock gating integrated cell; having active high enable clock transparent and active low enable clock hold low; with scan functionality for Clock network
C12T28SOI_LR_CNNOR2	X14, X33	2 input NOR for Clock network
C12T28SOI_LR_CNNAND2A	X17, X27	2 input NAND with A input inverted for Clock network
C12T28SOIDV_LR_SDFSYNCP RQ	X8	Metastable tolerant; Positive edge triggered Scan D flip-flop; with active low asynchronous Reset; having non-inverted

Cell Type	Drive Strength	Cell Description
		output Q only,Vdd rail at the bottom of the cell
C12T28SOI_LR_CNOR2	X16, X27	2 input Exclusive OR for Clock network

2.1.1.4. Poly Bias With 16nm

Table 5: Cell List

Cell Type	Drive Strength	Cell Description
C12T28SOI_LR_CNIV	X133, X16, X23, X31, X39, X47, X55, X5, X61, X70, X8, X94	Inverter with Balanced rise and fall delays for Clock network
C12T28SOIDV_LR_CNGFMUX21	X15, X30	2:1 Glitch-free MUX for Clock network,Vdd rail at the bottom of the cell
C12T28SOI_LR_CNAND2	X15, X20, X33	2 input AND for Clock network
C12T28SOIDV_LR_CNMUX41	X17, X27	4:1 non-inverting Multiplexer for Clock network,Vdd rail at the bottom of the cell
C12T28SOI_LR_CNAND3	X17, X25, X33	3 input AND for Clock network
C12T28SOIDV_LR_SDFSYNCPQ	X8	Metastable tolerant; Positive edge triggered Scan D flip-flop; having non-inverted output Q only,Vdd rail at the bottom of the cell
C12T28SOIDV_LR_SDFSYNCPQS	X8	Metastable tolerant; Positive edge triggered Scan D flip-flop; with active low asynchronous Preset; having non-inverted output Q only,Vdd rail at the bottom of the cell
C12T28SOI_LR_CNSDFPSQT	X15	Positive edge triggered Scan D flip-flop; with active low asynchronous Preset; having non-inverted output Q and non-inverted test output TQ for Clock network
C12T28SOI_LR_CNLDLRQ	X33	Active Low transparent Latch; with active low asynchronous Reset; having non-inverted output Q only
C12T28SOI_LR_CNNOR2A	X15, X27	2 input NOR with A input Inverted for Clock network
C12T28SOI_LR_DLYHFM4	X15, X7	Delay Cell for Hold Time Fixing
C12T28SOI_LR_CNNAND2	X15, X33	2 input NAND for Clock network
C12T28SOI_LR_DLYHFM8	X15, X54, X7	Delay Cell for Hold Time Fixing
C12T28SOI_LR_CNSDFPRQT	X15	Positive edge triggered Scan D flip-flop; with active low asynchronous Reset; having non-inverted output Q and non-inverted test output TQ for Clock network
C12T28SOI_LRP_CNHLS	X15, X22, X29, X36, X51, X58, X71, X7, X93	Design optimized to reduce dynamic power, Latch-based clock gating integrated cell; having active high enable clock transparent and active low enable clock hold low; with scan functionality for Clock network
C12T28SOI_LR_CNAO12	X33	2 input AND into 2 input OR
C12T28SOI_LR_CNOR4	X20, X27	4 input OR for Clock network

Cell Type	Drive Strength	Cell Description
C12T28SOI_LR_CNMUX21	X17, X33	2:1 non-inverting Multiplexer for Clock network
C12T28SOI_LR_CNBF	X133, X15, X22, X30, X38, X44, X4, X52, X59, X70, X7, X94	Buffer with Balanced rise and fall delays for Clock network
C12T28SOI_LR_CNOR3	X14, X20, X27	3 input OR for Clock network
C12T28SOI_LR_CNOR2	X15, X20, X33, X37	2 input OR for Clock network
C12T28SOI_LRPHP_CNHLS	X29, X36, X44, X51, X58, X71, X86	Design optimized to reduce dynamic power, Latch-based clock gating integrated cell; having active high enable clock transparent and active low enable clock hold low; with scan functionality for Clock network
C12T28SOI_LR_CNNOR2	X14, X33	2 input NOR for Clock network
C12T28SOI_LR_CNNAND2A	X17, X27	2 input NAND with A input inverted for Clock network
C12T28SOIDV_LR_SDFSYNCPRQ	X8	Metastable tolerant; Positive edge triggered Scan D flip-flop; with active low asynchronous Reset; having non-inverted output Q only, Vdd rail at the bottom of the cell
C12T28SOI_LR_CNXOR2	X16, X27	2 input Exclusive OR for Clock network

2.2. Cell Usage

Cell names starting with CNHLS* are used for clock gating. Clock gating module is used to disable clock to parts of the design that are not in use over that period. The cells have been set as "don't use" and "don't touch" in the .lib file

- Clocktree synthesis must only use the cells from CLOCK library (except DLY cells).
- For hold correction, following cells must be used:
 - DLY (delay cells)
 - CNIV
 - CNBF
- DLY cells are specifically meant for hold fixing only and no other cells other than DLY, CNIV, and CNBF must appear in hold correction.
- For datapath, all CN* cells can be used.

2.3. Delay Cell Specifications

Delay cells present in this library has been designed with Specific Targeted Delay at Best Process, 1.30V , -40C

Table 6: Cell Usage

Cell Type	Minimum Targeted Delay @ ff28_1.30V_m40C
C12T28SOI_LR_DLYHFM4X*_P0	40 ps
C12T28SOI_LR_DLYHFM8X*_P0	80 ps

3. Contact Information

For more information about this product/IP/Library or any problems or suggestions, please contact **HELPDESK** (<http://col2.cro.st.com/helpdesk>).

Non-ST users, please contact the respective Customer Support.



Please Read Carefully:

Information in this document is provided solely in connection with ST products. STMicroelectronics NV and its subsidiaries ("ST") reserve the right to make changes, corrections, modifications or improvements, to this document, and the products and services described herein at any time, without notice.

All ST products are sold pursuant to ST's terms and conditions of sale.

Purchasers are solely responsible for the choice, selection and use of the ST products and services described herein, and ST assumes no liability whatsoever relating to the choice, selection or use of the ST products and services described herein.

No license, express or implied, by estoppel or otherwise, to any intellectual property rights is granted under this document. If any part of this document refers to any third party products or services it shall not be deemed a license grant by ST for the use of such third party products or services, or any intellectual property contained therein or considered as a warranty covering the use in any manner whatsoever of such third party products or services or any intellectual property contained therein.

UNLESS OTHERWISE SET FORTH IN ST'S TERMS AND CONDITIONS OF SALE ST DISCLAIMS ANY EXPRESS OR IMPLIED WARRANTY WITH RESPECT TO THE USE AND/OR SALE OF ST PRODUCTS INCLUDING WITHOUT LIMITATION IMPLIED WARRANTIES OF MERCHANTABILITY, FITNESS FOR A PARTICULAR PURPOSE (AND THEIR EQUIVALENTS UNDER THE LAWS OF ANY JURISDICTION), OR INFRINGEMENT OF ANY PATENT, COPYRIGHT OR OTHER INTELLECTUAL PROPERTY RIGHT.

UNLESS EXPRESSLY APPROVED IN WRITING BY TWO AUTHORIZED ST REPRESENTATIVES, ST PRODUCTS ARE NOT RECOMMENDED, AUTHORIZED OR WARRANTED FOR USE IN MILITARY, AIR CRAFT, SPACE, LIFE SAVING, OR LIFE SUSTAINING APPLICATIONS, NOR IN PRODUCTS OR SYSTEMS WHERE FAILURE OR MALFUNCTION MAY RESULT IN PERSONAL INJURY, DEATH, OR SEVERE PROPERTY OR ENVIRONMENTAL DAMAGE. ST PRODUCTS WHICH ARE NOT SPECIFIED AS "AUTOMOTIVE GRADE" MAY ONLY BE USED IN AUTOMOTIVE APPLICATIONS AT USER'S OWN RISK.

Resale of ST products with provisions different from the statements and/or technical features set forth in this document shall immediately void any warranty granted by ST for the ST product or service described herein and shall not create or extend in any manner whatsoever, any liability of ST.

ST and the ST logo are trademarks or registered trademarks of ST in various countries.

Information in this document supersedes and replaces all information previously supplied.

The ST logo is a registered trademark of STMicroelectronics. All other names are the property of their respective owners.

:copyright: 2012 STMicroelectronics - All rights reserved

STMicroelectronics group of companies

Australia - Belgium - Brazil - Canada - China - Czech Republic - Finland - France - Germany - Hong Kong - India - Israel - Italy - Japan
- Malaysia - Malta - Morocco - Philippines - Singapore - Spain - Sweden - Switzerland - United Kingdom - United States of America

www.st.com